

Si5380 Rev D Data Sheet

Ultra-Low Phase Noise, 12-output JESD204B Clock Generator

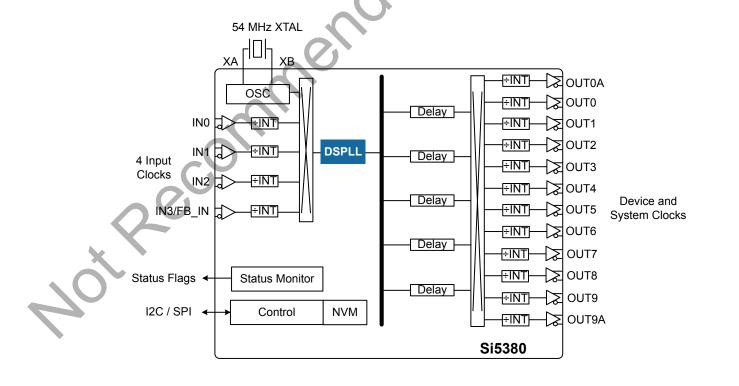
The Si5380 is a high performance, integer-based (M/N) clock generator for small cell applications which demand the highest level of integration and phase noise performance. Based on Silicon Laboratories' 4th generation DSPLL[™] technology, the Si5380 combines frequency synthesis and jitter attenuation in a highly integrated digital solution that eliminates the need for external VCXO and loop filter components. A low-cost, fixed-frequency crystal provides frequency stability for free-run and holdover modes. This all-digital solution provides superior performance that is highly immune to external board disturbances such as power supply noise.

Applications:

- JESD204B clock generation
- Remote Radio Units (RRU), Remote Access Networks (RAN), picocells, small cells
- Wireless base stations (3G, GSM, W-CDMA, 4G/LTE, LTE-A)
- Remote Radio Head (RRH), wireless repeaters, wireless backhaul
- Data conversion sampling clocks (ADC, DAC, DDC, DUC)

KEY FEATURES

- DSPLL eliminates external VCXO and analog loop filter components
- Supports JESD204B clocking: DCLK and SYSREF
- Ultra-low jitter of 65 fs
- Input frequency range:
 - External Crystal: 54 MHz
- Differential: 11.52 MHz to 737.28 MHz
- LVCMOS: 11.52 MHz to 245.76 MHz
- · Output frequency range:
 - Differential: 480 kHz to 1.47456 GHz
 - LVCMOS: 480 kHz to 245.76 MHz
- Status monitoring
- · Hitless switching
- Si5380: 4 input, 12 output, 64-QFN 9×9 mm



1. Feature List

The Si5380-D features are listed below:

- Digital frequency synthesis eliminates external VCXO and analog loop filter components
- Supports JESD204B clocking: DCLK and SYSREF
- Ultra-low jitter:
 - 65 fs typ (12 kHz to 20 MHz)
- Input frequency range:
 - Differential: 11.52 MHz to 737.28 MHz
 - LVCMOS: 11.52 MHz to 245.76 MHz
- Output frequency range:
 - Differential: up to 1.47456 GHz
 - · LVCMOS: up to 245.76 MHz
- Phase noise floor: –159 dBc/Hz
- Spur performance: –103 dBc max (relative to a 122.88 MHz carrier)
- Configurable outputs:
 - Signal swing: 200 to 3200 mVpp
 - Compatible with LVDS, LVPECL
 - LVCMOS 3.3, 2.5, or 1.8 V
- Output-output skew using same N-divider: 65 ps (Max)

- Adjustable output-output delay: 68 ps/step, ±128 steps
- Optional Zero Delay mode
- Independent output clock supply pins: 3.3, 2.5, or 1.8 V
- Core voltage:
 - VDD = 1.8 V ±5%
 - VDDA = 3.3 V ±5%
- Automatic free-run, lock, and holdover modes
- Programmable jitter attenuation bandwidth: 0.1 Hz to 100 Hz
- Hitless input clock switching
- Status monitoring (LOS, OOF, LOL)
- Serial interface: I2C or SPI In-circuit programmable with nonvolatile OTP memory
- ClockBuilderTM Pro software tool simplifies device configuration
- Si5380: 4 input, 12 output, 64-QFN 9×9 mm
- Temperature range: -40 to +85 °C
- Pb-free, RoHS-6 compliant

2. Ordering Guide

Table 2.1.	Ordering	Guide
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Ordering Part Number	Number of Outputs	Output Clock Frequency Range	Package	RoHS-6, Pb-Free	Temperature Range
Si5380A-D-GM	12	0.480 MHz to 1464.56 MHz	64-Lead 9x9 mm QFN	Yes	–40 to +85 °C
Si5380-D-EVB			Evaluation Board		3
Note: 1. Add an "R" at the end 2. Custom, factory pre-p format is: Si5380A-Dx	rogrammed devic	es are available. O	el options. Irdering part numbers are ass numerical sequence represe	signed by ClockBuilder enting the pre-program	Pro. Part number med configuration.
			~	en	
		Si	5380A-F	Rxxxx	-GM
Timing Clock Pr	oduct Family	_			
80 = Low Phase			Senerator		
A = Device grad	e (A)				
Product Revisio	n* +			l i	
		r (OPN) seque	ence ID**		
Custom ordering					1
Custom ordering			-40°C to +85°C)		
Package, ambie	ent temperatu		J, -40°C to +85°C) ←		
Package, ambie	ent temperatu	re range (QFN *See Ordering G	I, -40°C to +85°C) ← Guide table for current products; assigned by ClockBuilder F		
Package, ambie	ent temperatu	re range (QFN *See Ordering G ** 5 digits	Guide table for current produc		



3. Functional Description

The Si5380 is a high performance clock generator that is capable of synthesizing up to 10 unique integer related frequencies at any of the device's 12 outputs. The output clocks can be generated in free-run mode or synchronized to any one of the four external inputs. Clock generation is provided by Silicon Laboratories' 4th generation DSPLL technology which combines frequency synthesis and jitter attenuation in a highly integrated digital solution that eliminates the need for external VCXO and loop filter components. The Si5380 device is fully configurable using the I2C or SPI serial interface and has in-circuit programmable non-volatile memory.

3.1 Frequency Configuration

The DSPLL provides the synthesis for generating the output clock frequencies which are synchronous to the selected input clock frequency or free-running XTAL. It consists of a phase detector, a programmable digital loop filter, a high-performance ultra-low phase noise analog 15 GHz VCO, and a user configurable feedback divider. An internal oscillator (OSC) provides the DSPLL with a stable low-noise clock source for frequency synthesis and for maintaining frequency accuracy in the free-run or holdover modes. The oscillator simply requires an external, low cost 54 MHz fundamental mode crystal to operate. No other external components are required for frequency generation. A key feature of this DSPLL is that it provides immunity to external noise coupling from power supplies and other uncontrolled noise sources that normally exist on printed circuit boards.

3.1.1 Si5380 LTE Frequency Configuration

ot Recommended

The device's frequency configuration is fully programmable through the serial interface and can also be stored in non-volatile memory. The combination of flexible integer dividers and a high frequency VCO allows the device to generate multiple output clock frequencies for applications that require ultra-low phase noise and spurious performance. At the core of the device are the N dividers which determine the number of unique frequencies that can be generated from the device. The table below shows a list of some possible output frequencies for LTE applications. The Si5380's DSPLL core can generate up to five unique top frequencies. These frequencies are distributed to the output dividers using a configurable crosspoint mux. The R dividers allow further division for up to 10 unique integer-ratio related frequencies on the Si5380. The ClockBuilder Pro software utility provides a simple means of automatically calculating the optimum divider values (P, M, N and R) for the frequencies listed in the table below.

F _{IN} (N	IHz) ¹	LTE Device Clock Frequencies Fout (MHz) ²
15.	36	15.36
19.	20	19.20
30.	72	30.72
38.	40	38.40
61.	44	61.44
76.	80	76.80
122	.88	122.88
153	.60	153.60
184	.32	184.32
245	.76	245.76
307	.20	307.20
368	.64	368.64
491	.52	491.52
614	.40	614.40
737	.28	737.28
_	-	983.04
-	. 0	1228.80
_		1474.56
Note:		

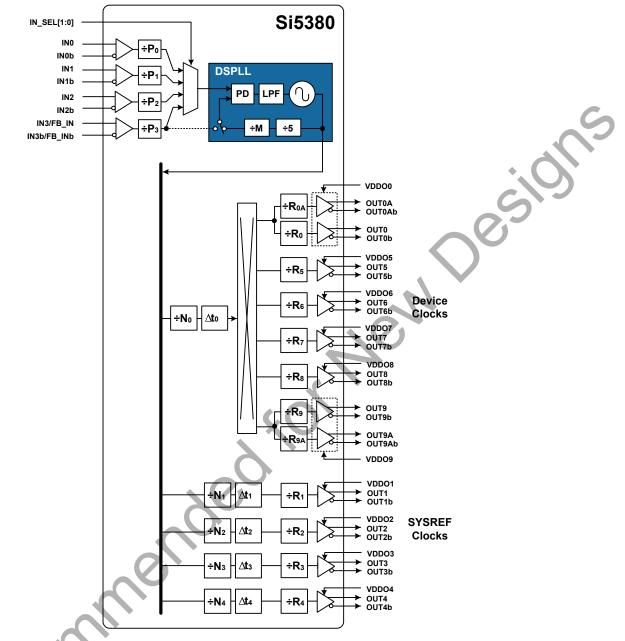
Table 3.1. Example of Possible LTE Clock Frequencies

1. The Si5380 locks to any one of the frequencies listed in the FIN column and generates LTE device clock frequencies.

2. R output dividers allow other frequencies to be generated. These are useful for applications like JESD204B SYSREF clocks.

3.1.2 Si5380 Configuration for JESD204B Clock Generation

The Si5380 can be used as a high performance, fully integrated JEDEC JESD204B jitter cleaner while eliminating the need for discrete VCXO and loop filter components. The Si5380 supports JESD204B subclass 0 and subclass 1 clocking by providing both device clocks (DCLK) and system reference clocks (SYSREF). The 12 clock outputs can be independently configured as device clocks or SYSREF clocks to drive JESD204B converters, FPGAs, or other logic devices. The Si5380 will clock up to four JESD204B targets using four or more DCLKs and four SYSREF clocks with adjustable delay. Each DCLK is grouped with a SYSREF clock in this configuration. If SYS-REF clocking is implemented in external logic, then the Si5380 will clock up to 12 JESD204B targets.Not limited to JESD204B applications, each of the 12 outputs is individually configurable as a high performance output for traditional clocking applications. An example of a JESD204B frequency configuration is shown in the figure below. In this case, the N dividers determine the device clock frequency and the R dividers provide the divided SYSREF clock which is used as the lower frequency frame clock. The N divider path also includes a configurable delay path (Δt) for controlling deterministic latency. The example shows a configuration where all the device clocks are controlled by a single delay path ($\Delta t0$) while the SYSREF clocks each have their own independent delay paths ($\Delta t1 - \Delta t4$), though other combinations are also possible. Delay is programmable in steps of 68 ps in the range of ±128 steps (±8.6 ns). See the 3.5.14 Output Skew Control ($\Delta t_0 - \Delta t_4$) section for details on skew control. The SYSREF clock is always periodic and can be controlled (on/off) without glitches by enabling or disabling its output through register writes.





3.1.3 DSPLL Loop Bandwidth

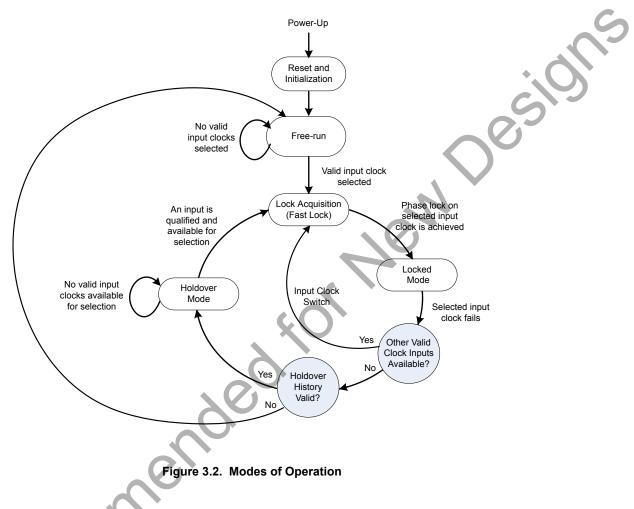
The DSPLL loop bandwidth determines the amount of input clock jitter attenuation. Register configurable DSPLL loop bandwidth settings in the range of 0.1 Hz to 100 Hz are available for selection. The DSPLL will always remain stable with less than 0.1 dB of peaking regardless of the DSPLL loop bandwidth selection.

3.1.4 Fastlock

Selecting a low DSPLL loop bandwidth (e.g., 1 Hz) will generally lengthen the lock acquisition time. The fastlock feature allows setting a temporary fastlock loop bandwidth that is used during the lock acquisition process. Higher fastlock loop bandwidth settings will enable the DSPLL to lock faster. Once lock acquisition has completed, the DSPLL's loop bandwidth will automatically revert to the DSPLL Loop Bandwidth setting. Fastlock loop bandwidth settings in the range of 100 Hz to 4 kHz are available for selection. The fastlock feature can be enabled or disabled by register configuration.

3.1.5 Modes of Operation

Once initialization is complete, the Si5380 operates in one of four modes: Free-run Mode, Lock Acquisition Mode, Locked Mode, or Holdover Mode. A state diagram showing the modes of operation is shown in the figure below. The following sections describe each of these modes in greater detail.



3.1.6 Initialization and Reset

When power is applied, the device begins an initialization period where it downloads default register values and configuration data from NVM and performs other initialization tasks. Communicating with the device through the serial interface is possible once this initialization period is complete. No clocks will be generated until the initialization is complete. There are two types of resets available. A hard reset is functionally similar to a device power-up. All registers will be restored to the values stored in NVM and all circuits, including the serial interface, will be restored to their initial state. A hard reset is initiated using the RSTb pin or by asserting the hard reset bit. A soft reset bypasses the NVM download. It is simply used to initiate register configuration changes.

3.1.7 Freerun Mode

Once power is applied to the Si5380 and initialization is complete, the device will automatically enter freerun mode. Output clocks will be generated on the outputs with their configured frequencies. The frequency accuracy of the generated output clocks in freerun mode is dependent on the frequency accuracy of the external crystal or reference clock on the XA/XB pins. For example, if the crystal frequency is ±100 ppm, then all the output clocks will be generated at their configured frequency ±100 ppm in freerun mode. Any change or drift of the crystal frequency or external reference on the XA/XB pins will be tracked at the output clock frequencies.

3.1.8 Lock Acquisition

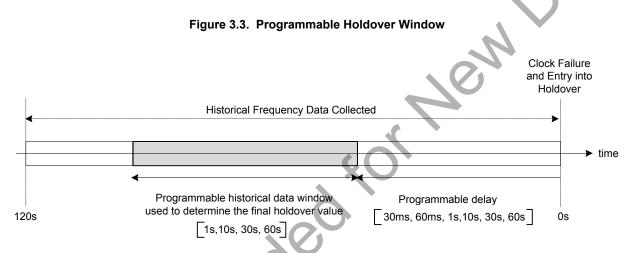
If a valid input clock is selected for synchronization, the DSPLL will automatically start the lock acquisition process. If the fast lock feature is enabled, the DSPLL will acquire lock using the Fastlock Loop Bandwidth setting and then transition to the DSPLL Loop Bandwidth setting when lock acquisition is complete. During lock acquisition the outputs will generate a clock that follows the VCO frequency change as it pulls-in to the input clock frequency.

3.1.9 Locked Mode

Once lock is achieved, the Si5380 will generate output clocks that are both frequency and phase locked to the input clock. The DSPLL will provide jitter attenuation of the input clock using the selected DSPLL loop bandwidth. At this point, any XTAL frequency drift inside of the loop bandwidth will not affect the output frequencies. When lock is achieved, the LOLb pin will output a logic high level. The LOL status bit and LOLb status pin will also indicate that the DSPLL is locked. See the 3.4.6 LOL Detection section for more details on LOLb detection time.

3.1.10 Holdover Mode

The DSPLL will automatically enter holdover mode when the selected input clock becomes invalid and no other valid input clocks are available for selection. The DSPLL uses an averaged input clock frequency as its final holdover frequency to minimize the disturbance of the output clock phase and frequency when an input clock suddenly fails. The holdover circuit stores up to 120 seconds of historical frequency data while the DSPLL is locked to a valid clock input. The final averaged holdover frequency value is calculated from a programmable window within the stored historical frequency data. Both the window size and the delay are programmable as shown in the figure below. The window size determines the amount of holdover frequency averaging. The delay value allows ignoring frequency data that may be corrupt just before the input clock failure.



When entering holdover, the DSPLL will pull the output clock frequencies referred to the calculated averaged holdover frequency. While in holdover, the output frequency drift is entirely dependent on the external crystal or external reference clock connected to the XA/XB pins. If a new clock input becomes valid, the DSPLL will automatically exit the holdover mode and re-acquire lock to the new input clock. This process involves pulling the output clock frequencies to achieve frequency and phase lock with the new input clock. This pull-in process is glitchless and its rate is controlled by the DSPLL bandwidth and the Fastlock bandwidth. These options are register programmable.

The DSPLL output frequency when exiting holdover can be ramped (recommend). Just before the exit is initiated, the difference between the current holdover frequency and the new desired frequency is measured. Using the calculated difference and a user-selectable ramp rate, the output is linearly ramped to the new frequency. The ramp rate can be 0.2 ppm/s, 40,000 ppm/s, or any of about 40 values in between. The DSPLL loop BW does not limit or affect ramp rate selections (and vice versa). CBPro defaults to ramped exit from holdover. The same ramp rate settings are used for both exit from holdover and ramped input switching. For more information on ramped input switching, see 3.3.5 Ramped Input Switching.

Note: If ramped holdover exit is not selected, the holdover exit is governed either by (1) the DSPLL loop BW or (2) a user-selectable holdover exit BW.

3.2 External Reference (XA/XB)

An external crystal (XTAL) is used in combination with the internal oscillator (OSC) to produce an ultra-low phase noise reference clock for the DSPLL and for providing a stable reference for the free-run and holdover modes. A simplified diagram is shown in the figure below. The Si5380 includes internal XTAL loading capacitors which eliminates the need for external capacitors and also has the benefit of reduced noise coupling from external sources. Refer to the Table 5.12 Crystal Specifications on page 34 for crystal specifications. A crystal frequency of 54 MHz is required, with a total accuracy of \pm 100 ppm* recommended for best performance. The Si5380 includes built-in XTAL load capacitors (C_L) of 8 pF, which are switched out of the circuit when using an external XO. The Si5380 Reference Manual provides additional information on PCB layout recommendations for the crystal to ensure optimum jitter performance. To achieve optimal jitter performance and minimize BOM cost, a crystal is recommended on the XA/XB reference input. A clock (e.g., XO) may be used in lieu of the crystal, but it may result in higher output jitter. See the *Si5380 Reference Manual* for more information. Selection between the external XTAL or REFCLK is controlled by register configuration. The internal crystal loading capacitors (C_L) are disabled in this mode. It is important to note that when using the REFCLK option the phase noise of the outputs is directly affected by the phase noise of the external XO reference. Refer to the Table 5.3 Input Clock Specifications on page 24 for REFCLK requirements when using the REFCLK mode.

Note: Including initial frequency tolerance and frequency variation over the full operating temperature range, voltage range, load conditions, and aging.

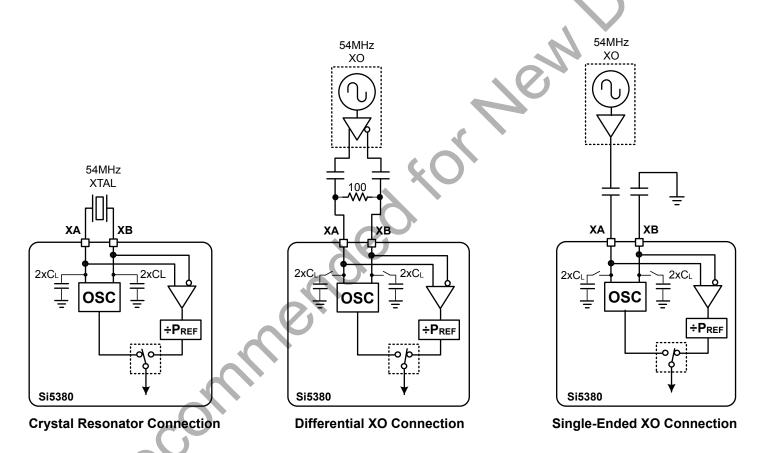


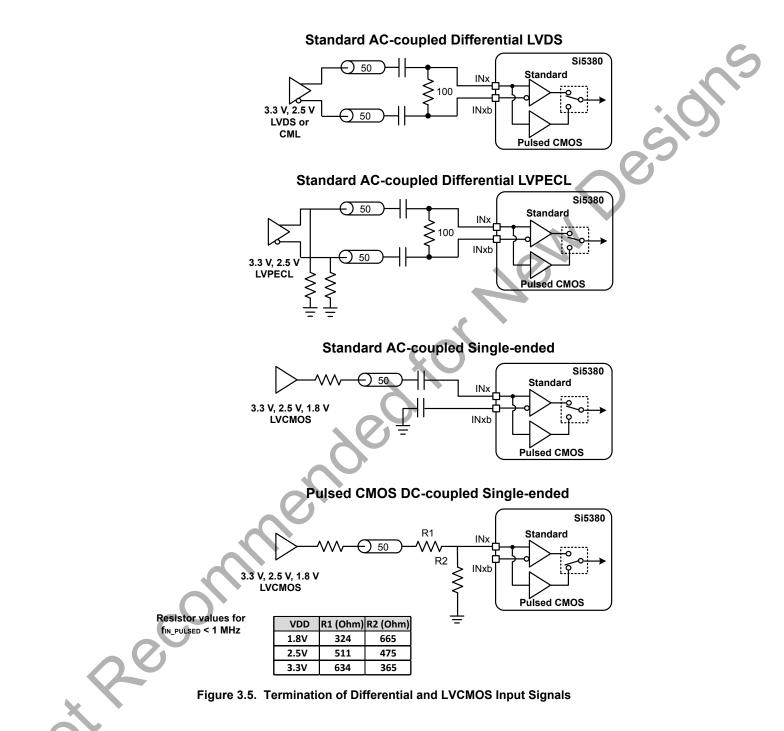
Figure 3.4. XAXB Crystal Resonator and External Reference Clock Connection Options

3.3 Inputs (IN0, IN1, IN2, IN3/FB_IN)

Four clock inputs are available to synchronize the DSPLL. The inputs are compatible with both single-ended and differential signals. Input selection can be manual (pin or register controlled) or automatic with definable priorities.

3.3.1 Input Configuration and Terminations

Each of the inputs can be configured as differential or single-ended LVCMOS. The recommended input termination schemes are shown in the figure below. Standard 50% duty cycle signals must be ac-coupled, while low duty cycle Pulsed CMOS signals can be DC-coupled. Unused inputs can be disabled and left unconnected when not in use.



3.3.2 Manual Input Selection (IN0, IN1, IN2, IN3/FB_IN)

Input clock selection can be made manually using the IN_SEL[1:0] pins or through a register. A register bit determines input selection as pin selectable or register selectable. The IN_SEL pins are selected by default. If there is no clock signal on the selected input, the device will automatically enter free-run or holdover mode.

* NOTE: When the zero delay mode is enabled, IN3 becomes the feedback input (FB_IN) and is not available for selection as a clock input.

IN_SEL[1:0] Selected Input 0 0 IN0 0 1 IN1 1 0 IN2 1 1 IN3*

Table 3.2. Manual Input Selection Using IN_SEL[1:0] Pins

3.3.3 Automatic Input Switching (IN0, IN1, IN2, IN3/FB_IN)

An automatic input selection state machine is available in addition to the manual switching option. In automatic mode, the selection criteria is based on reference qualification, input priority, and the revertive option. Only references which are valid can be selected by the automatic state machine. If there are no valid references available, the DSPLL will enter the holdover mode. With revertive switching enabled, the highest priority input with a valid reference is always selected. If an input with a higher priority becomes valid, then an automatic switchover to that input will be initiated. With non-revertive switching, the active input will always remain selected while it is valid. If it becomes invalid, an automatic switchover to a valid input with the highest priority will be initiated.

3.3.4 Hitless Input Switching

Hitless switching is a feature that prevents a phase transient from propagating to the output when switching between two frequency locked clock inputs that have a fixed phase difference between them. A hitless switch can only occur when the two input frequencies are frequency locked meaning that they have to be exactly at the same frequency, or have an integer frequency relationship to each other. When this feature is enabled, the DSPLL simply absorbs the phase difference between the two input clocks during an input switch. When disabled (normal switching), the phase difference between the two inputs is propagated to the output at a rate determined by the DSPLL loop bandwidth.

3.3.5 Ramped Input Switching

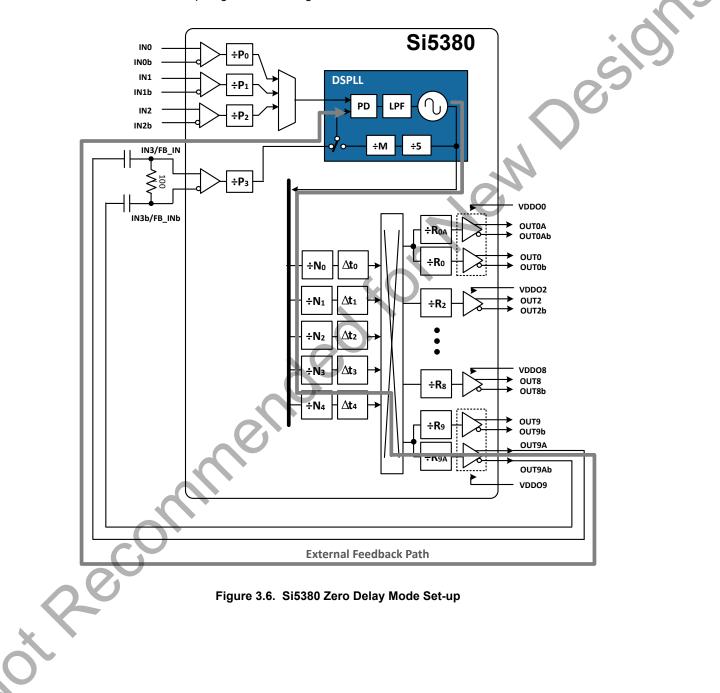
When switching between two plesiochronous input clocks (i.e., the frequencies are "almost the same" but not quite), ramped input switching should be enabled to ensure a smooth transition between the two inputs. Ramped input switching avoids frequency transients and overshoot when switching between frequencies and so is the default switching mode in CBPro. The feature should be turned off when switching between input clocks that are always frequency locked (i.e., are always the same exact frequency). The same ramp rate settings are used for both holdover exit and clock switching. For more information on ramped exit from holdover, see 3.1.10 Holdover Mode.

3.3.6 Glitchless Input Switching

The DSPLL has the ability of switching between two input clocks that are up to 40 ppm apart in frequency. The DSPLL will pull-in to the new frequency using the DSPLL loop bandwidth or using the Fastlock loop bandwidth if it is enabled. The loss of lock (LOL) indicator will be asserted while the DSPLL is pulling-in to the new clock frequency. There will be no output runt pulses generated at the output. Glitchless input switching is available regardless of whether the hitless switching feature is enabled or disabled.

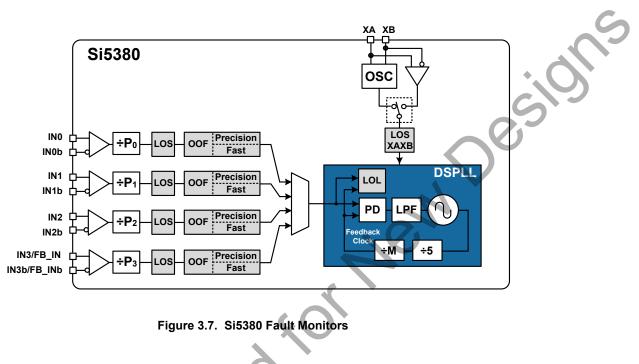
3.3.7 Zero Delay Mode

A zero delay mode is available for applications that require fixed and consistent minimum delay between the selected input and outputs. The zero delay mode is configured by opening the internal feedback loop through software configuration and closing the loop externally as shown in the figure below. This helps to cancel out the internal delay introduced by the dividers, the crosspoint, the input, and the output drivers. Any one of the outputs can be fed back to the IN3/FB_IN pins, although using the output driver that achieves the short-est trace length will help to minimize the input-to-output delay. The OUT9A and IN3/FB_IN pins are recommended for the external feedback connection. The FB_IN input pins must be terminated and ac-coupled when zero delay mode is used. A differential external feedback path connection is necessary for best performance. The order of the OUT9A and FB_IN polarities is such that they may be routed on the device side of the PCB without requiring vias or needing to cross each other.



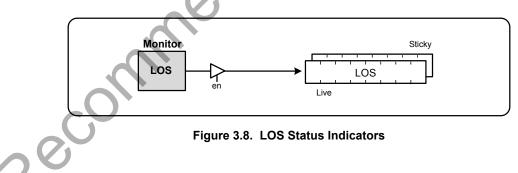
3.4 Fault Monitoring

All four input clocks (IN0, IN1, IN2, IN3/FB_IN) are monitored for loss of signal (LOS) and out-of-frequency (OOF) as shown in the figure below. The reference at the XA/XB pins is also monitored for LOS since it provides a critical reference clock for the DSPLL. The DSPLL also has a Loss Of Lock (LOL) indicator, which is asserted when the DSPLL has lost synchronization with the selected input clock.



3.4.1 Input LOS Detection

The loss of signal monitor measures the period of each input clock cycle to detect phase irregularities or missing clock edges. Each of the input LOS circuits have their own programmable sensitivity which allows ignoring missing edges or intermittent errors. Loss of signal sensitivity is configurable using the ClockBuilder Pro utility. The LOS status for each of the monitors is accessible by reading a status register. The live LOS register always displays the current LOS state and a sticky register always stays asserted until cleared. An option to disable any of the LOS monitors is also available.

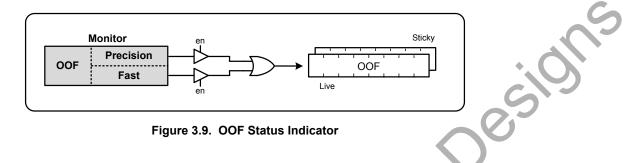


3.4.2 XA/XB LOS Detection

An LOS monitor is available to ensure that the external crystal or reference clock is valid. By default, the output clocks are disabled when XAXB LOS is detected. This feature can be disabled such that the device will continue to produce output clocks when XAXB LOS is detected. See the 3.5.11 Output Disable During XAXB_LOS section for details.

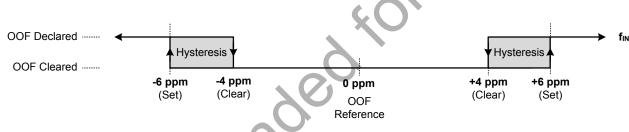
3.4.3 OOF Detection

Each input clock is monitored for frequency accuracy with respect to a OOF reference which it considers as its "0_ppm" reference. This OOF reference can be selected as either: XAXB, IN0, IN1, IN2 or IN3. IN3 is only available as the OOF reference when not in ZDM. The final OOF status is determined by the combination of both a precise OOF monitor and a fast OOF monitor as shown in the figure below. An option to disable either monitor is also available. The live OOF register always displays the current OOF state, and its sticky register bit stays asserted until cleared.



3.4.4 Precision OOF Monitor

The Precision OOF monitor circuit measures the frequency of all input clocks to within ± 1 ppm accuracy with respect to the frequency at the XA/XB pins. The OOF monitor considers the frequency at the XA/XB pins as its 1/16 ppm OOF reference. A valid input frequency is one that remains within the OOF frequency range which is register configurable up to ± 500 ppm in steps of 1/16 ppm. A configurable amount of hysteresis is also available to prevent the OOF status from toggling at the failure boundary. An example is shown in the figure below. In this case the OOF monitor is configured with a valid frequency range of ± 6 ppm and with 2 ppm of hysteresis. An option to use one of the input pins (IN0–IN3) as the 0 ppm OOF reference instead of the XA/XB pins is available. This option is register configurable.





3.4.5 Fast OOF Monitor

Because the precision OOF monitor needs to provide 1/16 ppm of frequency measurement accuracy, it must measure the monitored input clock frequencies over a relatively long period of time. This may be too slow to detect an input clock that is quickly ramping in frequency. An additional level of OOF monitoring called the Fast OOF monitor runs in parallel with the precision OOF monitors to quickly detect a ramping input frequency. The Fast OOF monitor asserts OOF on an input clock frequency that has changed by 1,000 to 16,000 ppm.

3.4.6 LOL Detection

A loss of lock (LOL) monitor asserts the LOL bit when the DSPLL has lost synchronization with the selected input clock. There is also a dedicated active-low LOLb pin which reflects the loss of lock condition. The LOL monitor measures the frequency difference between the input and feedback clocks at the phase detector. There are two LOL frequency monitors, one that sets the LOL indicator (LOL Set) and another that clears the indicator (LOL Clear). A block diagram of the LOL monitor is shown in the figure below. The live LOL register always displays the current LOL state and a sticky register always stays asserted until cleared. The LOLb pin reflects the current state of the LOL monitor.

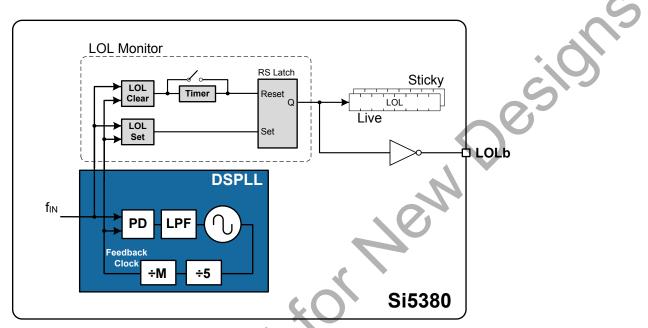
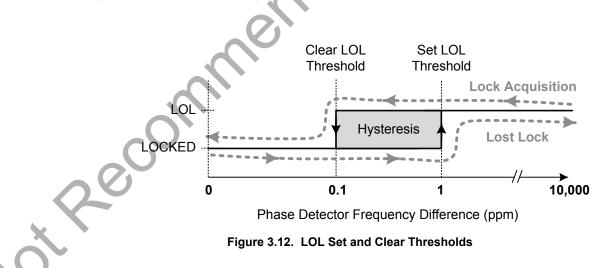


Figure 3.11. LOL Status Indicators

Each of the frequency monitors have adjustable sensitivity which is register configurable from 0.1 ppm to 10,000 ppm. Having two separate frequency monitors allows for hysteresis to help prevent chattering of LOL status. An example configuration where LOCK is indicated when there is less than 0.1 ppm frequency difference at the inputs of the phase detector and LOL is indicated when there is more than 1 ppm frequency difference is shown in the figure below.



An optional timer is available to delay clearing of the LOL indicator to allow additional time for the DSPLL to completely phase lock to the input clock. The timer is also useful to prevent the LOL indicator from toggling or chattering as the DSPLL completes lock acquisition. The configurable delay value depends on frequency configuration and loop bandwidth of the DSPLL and is automatically calculated using the ClockBuilder Pro utility.

3.4.7 Interrupt Pin INTRb

An interrupt pin INTRb indicates a change in state of the status indicators shown in the figure below. All of the status indicators are maskable to prevent assertion of the interrupt pin. The state of the INTRb pin is reset by clearing the status register that caused the interrupt. The sticky version of the fault monitors is used for this function to ensure that the fault condition is still available when responding to the interrupt.

Si5380)
OOF_FLG 0x0012[4]	i S
LOS_FLG 0x0012[1]	5
OOF_FLG 0x0012[5]	
OOF_FLG 0x0012[6]	XÓ□ INTRb
OOF_FLG 0x0012[7]	
CAL_FLG 0x0014[5]	
SYSINCAL_FLG 0x0011[0]	
LOSXAXB_FLG 0x0011[1]	
LOSREF_FLG 0x0011[2]	
XAXB_ERR_FLG 0x0011[3]	
SMBUS_TIMEOUT_FLG 0x0011[5]	J

Figure 3.13. Interrupt Triggers and Masks

3.5 Outputs

The Si5380 supports 12 differential output drivers which can be independently configured as differential or LVCMOS.

3.5.1 Output Crosspoint

The output crosspoint allows any of the N dividers to connect to any of the clock outputs.

3.5.2 Output Signal Format

The differential output amplitude and common mode voltage are both fully programmable covering a wide variety of signal formats including LVPECL, LVDS, HCSL, and CML. In addition to supporting differential signals, any of the outputs can be configured as LVCMOS (3.3 V, 2.5 V, or 1.8 V) drivers providing up to 24 single-ended outputs, or any combination of differential and single-ended outputs.

3.5.3 Output Terminations

The output drivers support both ac-coupled and dc-coupled terminations as shown in the following figure.

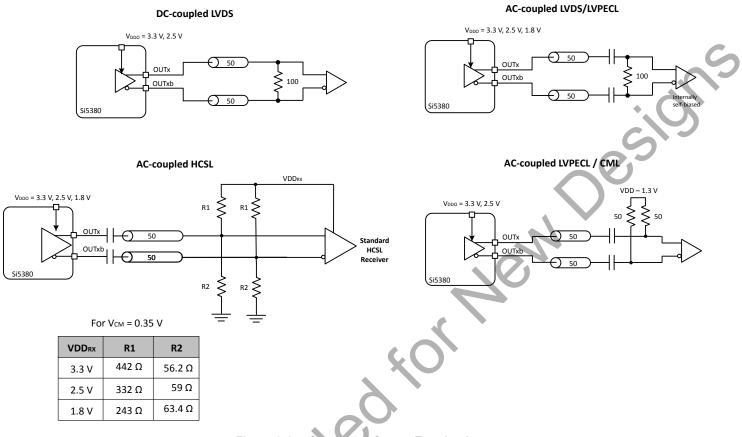


Figure 3.14. Supported Output Terminations

3.5.4 Programmable Common Mode Voltage For Differential Outputs

The common mode voltage (V_{CM}) for the differential modes is programmable in 100 mV increments from 0.7 V to 2.3 V depending on the voltage available at the output's VDDO pin. Setting the common mode voltage is useful when dc-coupling the output drivers.

3.5.5 LVCMOS Output Terminations

LVCMOS outputs are dc-coupled with source-side series termination as shown in the figure below.

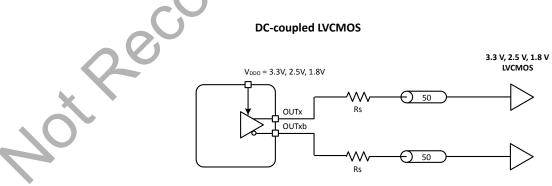


Figure 3.15. LVCMOS Output Terminations

3.5.6 LVCMOS Output Impedance and Drive Strength Selection

Each LVCMOS driver has a configurable output impedance to accommodate different trace impedances and drive strengths. A source termination resistor is recommended to help match the selected output impedance to the trace impedance. There are three programmable output impedance selections for each VDDO options as shown in the table below.

Table 3.3.	Typical	Output	Impedance (Z _S)
------------	---------	--------	-----------------------------

VDDO		CMOS_DRIVE_Selection	
	OUTx_CMOS_DRV = 1	OUTx_CMOS_DRV = 2	OUTx_CMOS_DRV = 3
3.3 V	38 Ω	30 Ω	22 Ω
2.5 V	43 Ω	35 Ω	24 Ω
1.8 V	_	46 Ω	31 Ω

3.5.7 LVCMOS Output Signal Swing

The signal swing (VOL/VOH) of the LVCMOS output drivers is set by the voltage on the VDDO pins. Each output driver has its own VDDO pin allowing a unique output voltage swing for each of the LVCMOS drivers. OUT0 and OUT0A share the same VDDO pin. OUT9 and OUT9A also share the VDDO pin. All other outputs have their own individual VDDO pins.

3.5.8 LVCMOS Output Polarity

When a driver is configured as an LVCMOS output it generates a clock signal on both pins (OUTx and OUTxb). By default the clock on the OUTxb pin is generated with the same polarity (in phase) with the clock on the OUTx pin. The polarity of these clocks is configurable enabling complimentary clock generation and/or inverted polarity with respect to other output drivers.

3.5.9 Output Enable/Disable

The OEb pin provides a convenient method of disabling or enabling all of the output drivers at the same time. When the OEb pin is held high all outputs will be disabled. When held low, the outputs will all be enabled. Outputs in the enabled state can still be individually disabled through register control.

3.5.10 Output Disable During LOL

By default, a DSPLL that is out of lock will generate either free-running clocks or generate clocks in holdover mode. There is an option to disable the outputs when a DSPLL is LOL. This option can be useful to force a downstream PLL into holdover.

3.5.11 Output Disable During XAXB_LOS

The internal oscillator circuit (OSC) in combination with the external crystal (XTAL) provides a critical function for the operation of the DSPLLs. In the event of a crystal failure, the device will assert an XAXB_LOS alarm. By default, all outputs will be disabled during assertion of the XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm, but the frequency accuracy and stability will be indeterminate during this fault condition. The internal oscillator circuit (OSC) in combination with the external crystal (XTAL) provides a critical function for the operation of the DSPLLs. In the event of a crystal failure, the device will assert an XAXB_LOS alarm. By default, all outputs will be disabled during assertion of the XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm. There is an option to leave the outputs enabled during an XAXB_LOS alarm.

3.5.12 Output Driver State When Disabled

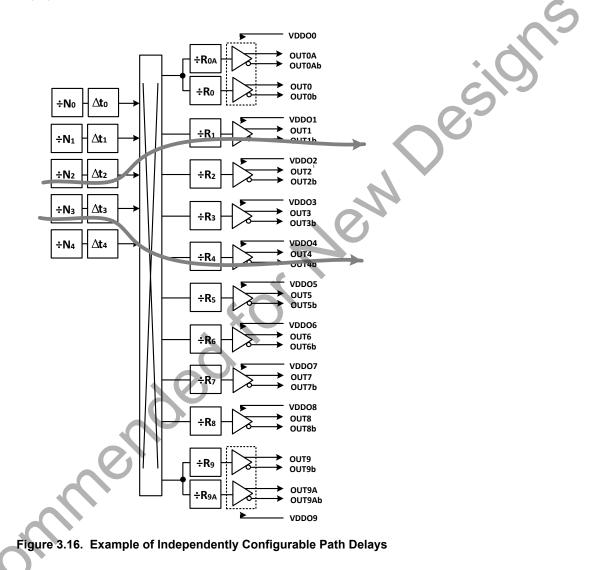
The disabled state of an output driver is configurable as either disable low or disable high.

3.5.13 Synchronous Enable/Disable Feature

The output drivers provide a selectable synchronous enable/disable feature. Output drivers with synchronous disable active will wait until a clock period has completed before the driver is disabled or enabled. This prevents unwanted shortened pulses from occurring when enabling or disabling an output. When this feature is turned off, the output clock will disable immediately without waiting for the clock period to complete.

3.5.14 Output Skew Control ($\Delta t_0 - \Delta t_4$)

The Si5380 uses independent dividers (N0 - N4) to generate up to 5 unique frequencies to its 12 outputs through a crosspoint switch. A delay path (Δ t0 - Δ t4) associated with each of these dividers is available for applications that need a specific output skew configuration. This is useful for compensating PCB trace delay differences or for applications that require quadrature clock generation. The resolution of the phase adjustment is approximately 68 ps per step up to 128 steps of added phase delay (+8.6 ns late), or 128 steps of negative delay (-8.6 ns early). Phase adjustments are register configurable. An example of generating two frequencies with unique configurable path delays is shown in the following figure.



All phase delay values are restored to their default values after power-up, power-on reset, or hardware reset using the RSTb pin. Phase delay default values can be written to NVM allowing a custom phase offset configuration at power-up or after power-on reset, or after a hardware reset using the RSTb pin.

3.5.15 Output Divider (R) Synchronization

All the output R dividers are reset to a known state during the power-up initialization period. This ensures consistent and repeatable phase alignment across all output drivers. Resetting the device using the RSTb pin or asserting the reset bit will have the same result. Asserting the sync register bit provides another method of realigning the R dividers without resetting the device.

3.6 Power Management

Unused inputs and output drivers can be powered down when unused. Consult the Si5380 Reference Manual and ClockBuilder Pro configuration utility for details.

3.6.1 Power Down Pin (PDNb)

A power down pin is provided to force the device in a low power mode. The device's configuration will be maintained but no output clocks will be generated. Most of the internal blocks will be shut down but device communication via the serial interface will still be available. When the PDNb pin is pulled low the outputs will shut down without glitching (the clock's complete period will be generated before shutting down). When PDNb is released the device will start generating clocks without glitches. The device will generate free-running clocks until the DSPLL has acquired lock to the selected input clock source.

3.7 In-Circuit Programming

The Si5380 is fully configurable using the serial interface (I2C or SPI). At power-up, the device downloads its default register values from internal non-volatile memory (NVM). Application specific default configurations can be written into NVM allowing the device to generate specific clock frequencies at power-up. Writing default values to NVM is in-circuit programmable with normal operating power sup-ply voltages applied to its VDD and VDDA pins. The NVM is writable two times. Once a new configuration has been written to NVM, the old configuration is no longer accessible. Refer to the Si5380 Reference Manual for a detailed procedure for writing registers to NVM.

3.8 Serial Interface

Configuration and operation of the Si5380 is controlled by reading and writing registers using the I2C or SPI interface. The I2C_SEL pin selects I2C or SPI operation. The Si5380 supports communication with a 3.3 V or 1.8 V host by setting the IO_VDD_SEL configuration bit. The SPI mode supports 4-wire or 3-wire by setting the SPI_3WIRE configuration bit. See the Si5380 Reference Manual for details.

3.9 Custom Factory Preprogrammed Devices

For applications where a serial interface is not available for programming the device, custom pre-programmed parts can be ordered with a specific configuration written into NVM. A factory pre-programmed device will generate clocks at power-up. Custom, factory-pre-programmed devices are available. Use the ClockBuilder Pro custom part number wizard (www.silabs.com/clockbuilderpro) to quickly and easily request and generate a custom part number for your configuration.

In less than three minutes, you will be able to generate a custom part number with a detailed data sheet addendum matching your design's configuration. Once you receive the confirmation email with the data sheet addendum, simply place an order with your local Silicon Labs sales representative. Samples of your pre-programmed device will ship to you typically within two weeks.

3.10 Enabling Features and/or Configuration Settings Not Available in ClockBuilder Pro for Factory Pre-programmed Devices

As with essentially all software utilities, ClockBuilder Pro is continuously updated and enhanced. By registering at www.silabs.com and opting in for updates to software, you will be notified whenever changes are made and what the impact of those changes are. This update process will ultimately enable ClockBuilder Pro users to access all features and register setting values documented in this data sheet and the Si5380 Reference Manual.

However, if you must enable or access a feature or register setting value so that the device starts up with this feature or a register setting, but the feature or register setting is NOT yet available in CBPro, you must contact a Silicon Labs applications engineer for assistance. Examples of this type of feature or custom setting are the customizable output amplitude and common voltages for the clock outputs. After careful review of your project file and custom requirements, all Silicon Labs applications engineer will email back your CBPro project file with your specific features and register settings enabled, using what is referred to as the manual "settings override" feature of CBPro. "Override" settings to match your request(s) will be listed in your design report file. Examples of setting "overrides" in a CBPro design report are shown below:

Table 3.4. Setting Overrides

Location	Name	Туре	Target	Dec Value	Hex Value
0x0535[0]	FORCE_HOLD	No NVM	N/A	1	0x1
0128[6:4]	OUT6_AMPL	User	OPN and EVB	5	0x5

Once you receive the updated design file, simply open it in CBPro. After you create a custom OPN, the device will begin operation after startup with the values in the NVM file, including the Silicon Labs-supplied override settings.

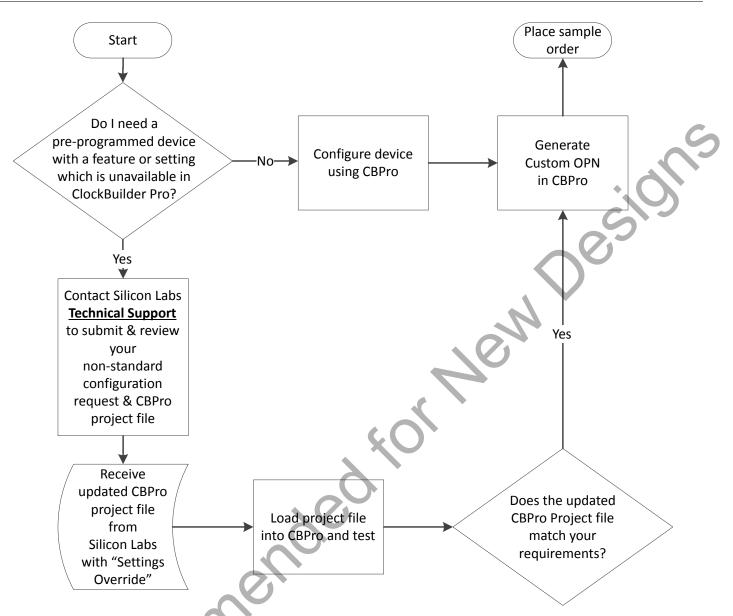


Figure 3.17. Flowchart to Order Custom Parts with Features not Available in CBPro

Note: Contact Silicon Labs Technical Support at www.silabs.com/support/Pages/default.aspx.

4. Register Map

This document provides a brief list of available registers. For a complete list of registers and settings, please refer to the Si5380 Reference Manual. Recommended for New Desit

5. Electrical Specifications

Table 5.1. Recommended Operating Conditions ¹

Parameter	Symbol	Min	Тур	Мах	Unit
Ambient Temperature	T _A	-40	25	85	°C
Maximum Junction Temperature	T _{JMAX}	_	_	125	O°
Core Supply Voltage	V _{DD}	1.71	1.80	1.89	• V
	V _{DDA}	3.14	3.30	3.47	V
Output Driver Supply Voltage	V _{DDO}	3.14	3.30	3.47	V
		2.37	2.50	2.62	V
		1.71	1.80	1.89	V

Note:

1. All minimum and maximum specifications are guaranteed and apply across the recommended operating conditions. Typical val-Reconnended ues apply at nominal supply voltages and an operating temperature of 25 °C unless otherwise noted.

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Core Supply Current ^{1,2}	I _{DD}		_	190	310	mA
	I _{DDA}		—	125	135	mA
Output Buffer Supply Current ^{2, 5}	I _{DDO}	LVPECL Output ³	_	36	41	mA
		@ 1474.56 MHz			•	
		LVPECL Output ³	—	22	26	mA
		@ 153.6 MHz			0.5	
		LVDS Output ³	—	25	29	mA
		@ 1474.56 MHz				
		LVDS Output ³	_	15	18	mA
		@ 153.6 MHz				
		3.3 V LVCMOS Output ⁴	_	22	30	mA
		@ 153.6 MHz				
		2.5 V LVCMOS Output ⁴	-	18	23	mA
		@ 153.6 MHz)			
		1.8 V LVCMOS Output ⁴	_	12	16	mA
		@ 153.6 MHz				
Total Power Dissipation ^{1, 2}	Pd	Typical Outputs	_	1300	1600	mW

Table 5.2. DC Characteristics

Notes:

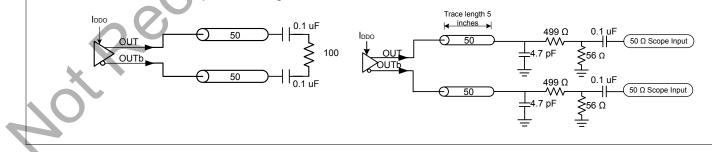
1. Si5380 test configuration: 3 × 3.3 V LVPECL outputs enabled at 122.88 MHz, 2 × 3.3 V LVPECL outputs enabled at 491.52 MHz, 1 × 3.3 V LVPECL output enabled at 983.04 MHz. Excludes power in termination resistors.

2. Detailed power consumption for any configuration can be estimated using ClockBuilder Pro when an evaluation board (EVB) is not available. All EVBs support detailed current measurements for any configuration.

3. Differential outputs terminated into an ac-coupled 100 Ω load.

4. LVCMOS outputs measured into a 5-inch 50 Ω PCB trace with 5 pF load. The LVCMOS outputs were set to OUTx_CMOS_DRV=3, which is the strongest driver setting. Refer to the Si5380 Reference Manual for more details on register settings.

5. VDDO0 supplies power to both OUT0 and OUT0A buffers. Similarly, VDDO9 supplies power to both OUT9 and OUT9A buffers. Differential Output Test Configuration LVCMOS Output Test Configuration



Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Standard Input Buffer with D	ifferential or Singl	e-Ended/LVCMOS—AC-co	upled (IN0, IN	1, IN2, IN3/FE	5_IN)	
Input Frequency Range	f _{IN_DIFF}	Differential	11.52	_	737.28	MHz
	f _{IN_SE}	All Single-ended Signals	11.52	_	245.76	MHz
		(including LVCMOS)				
Voltage Swing ¹	V _{IN}	Differential AC-coupled	100	_	1800	mVpp_se
		F _{IN} < 245.76 MHz				\mathbf{D}
		Differential AC-coupled	225	_	1800	mVpp_se
		245.76 MHz < F _{IN} < 737.28 MHz				
		Single-Ended AC-coupled	100	14	3600	mVpp_se
		F _{IN} < 245.76 MHz		2		
Slew Rate ^{2, 3}	SR		400	-	_	V/µs
Duty Cycle	DC		40		60	%
Capacitance	C _{IN}	. (-	0.3	_	pF
Input Resistance	R _{IN}) _	16	_	kΩ
Pulsed CMOS Input Buffer—	DC-coupled (IN0, I	IN1, IN2, IN3/FB_IN) ⁴				
Input Frequency	fin_pulsed_cm	20	11.52	_	245.76	MHz
Input Voltage Thresholds ⁴	VIL		-0.2		0.4	V
	V _{IH}		0.8	_	_	V
Slew Rate ^{2, 3}	SR	6	400	_	_	V/µs
Duty Cycle	DC	Clock Input	40		60	%
Minimum Pulse Width	PW	Pulse Input	1.6	_	_	ns
Input Resistance	R _{IN}		_	8	_	kΩ
REFCLK (applied to XA/XB))					
REFCLK Frequency ⁵	f _{IN_REF}	Frequency required for op- timum performance	_	54	_	MHz
Total Frequency Tolerance ⁶	f _{RANGE}		-100	—	+100	ppm
Input Voltage Swing	V _{IN_SE}		365	—	2000	mVpp_se
	V _{IN_DIFF}		365	_	2500	mVpp_diff
Slew Rate ^{2 , 3}	SR	Imposed for best phase noise performance	400	_	_	V/µs
Input Duty Cycle	DC		40	_	60	%

Table 5.3. Input Clock Specifications

Si5380 Rev D Data Sheet Electrical Specifications

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Notes:		1				
1. Voltage swing is specified	l as single-ended m	Vpp.				
	OUTx Vcm Vcm OUTxb	Vpp_se	Vpp	_diff = 2*Vpp_se		
2. Imposed for phase noise	performance.					C
3. Rise and fall times can be	estimated using the	e following simplified equatio	n: tr/tf ₈₀₋₂₀ = ((0.8 – 0.2) * V	IN Vpp se)/SR	
cycle significantly less that thresholds (VIL, VIH) of t dc-coupled Pulsed LVCM	n 50%. A common ne input buffer are n OS in the in the Si5	single-end LVCMOS input cl application example is a low on-standard (0.40 and 0.80 \ 380 Reference Manual . Oth n Figure 3.14 Supported Out	frequency vid /, respectively erwise, for sta	eo frame sync), refer to the ndard LVCMC	pulse. Since t input attenuato S input clocks	he input or circuit for
5. The REFCLK frequency	or the Si5380 is fixe	d at 54 MHz. Contact Silicon	Labs technica	al support for r	nore informatio	on.
6. Includes initial tolerance,	drift after reflow, cha	ange over temperature (–40 °	°C to +85 °C),	V _{DD} variation	, load pulling, a	and aging.

Table 5.4. Serial and Control Input Pin Specifications

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Si5380 Serial and Control Inp	ut Pins (I2C_SEL,	, IN_SEL[1:0], RSTb, OEb, 3	SYNCb, PDNb	o, A1/SDO, SE	DA/SDIO, SCL	K, A0/CSb)
Input Voltage Thresholds	V _{IL}		_		0.3xV _{DDIO} 1	V
	V _{IH}		0.7 x V _{DDIO} 1	_	-	V
Input Capacitance	C _{IN}		_	2	_	pF
Input Resistance	ΙL	\mathbf{N}	_	20	_	kΩ
Minimum Pulse Width	PW	RSTb, SYNCb, PDNb	100	_	_	ns
Natas						

Note:

1. V_{DDIO} is determined by the IO_VDD_SEL bit. It is selectable as V_{DDA} or V_{DD}. See the Si5380 Reference Manual for more details on the register settings.

Parameter	Symbol	Test Cor	ndition	Min	Тур	Max	Unit
Output Frequency	f _{OUT}			0.480	—	1474.56	MHz
Duty Cycle	DC	f ≤ 400	MHz	48	_	52	%
		f > 400	MHz	45	_	55	%
Output-Output Skew	Т _{SK}	Outputs at 73 connected to "N-divi	the same	_	_	65	ps
		Outputs at 73 connected to di vider	ifferent "N-di-	_	-	90	ps
OUT-OUTb Skew	T _{SK_OUT}	Measured from to negative c		_	0	50	ps
Dutput Voltage Amplitude ¹	V _{OUT}	V _{DDO} =	LVDS	350	430	510	mVpp_se
		3.3 V or			2		
		2.5 V or					
		1.8 V					
		V _{DDO} = 3.3 V or 2.5 V	LVPECL	640	750	900	
Common Mode Voltage ¹	V _{CM}	V _{DDO} =	LVDS	1.10	1.2	1.3	V
		3.3 V	LVPECL	1.90	2.0	2.1	
		V _{DDO} =	LVPECL	1.1	1.2	1.3	-
		2.5 V	LVDS				
	C	V _{DDO} = 1.8 V	sub-LVDS	0.8	0.9	1.00	
Rise and Fall Times (20% to 80%)	t _R /t _F				100	150	ps
Differential Output Impedance	Zo			_	100	_	Ω
Power Supply Noise Rejection ²	PSRR	10 kHz sinus	oidal noise	_	-101	_	dBc
()		100 kHz sinus	soidal noise	_	-96	_	dBc
		500 kHz sinus	soidal noise	-	-99	_	dBc
		1 MHz sinus	oidal noise	_	-97	_	dBc
Output-Output Crosstalk ³	XTALK	Measured spu		-	-72	_	dB

Table 5.5. Differential Clock Output Specifications

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Notes:	•					
	dependently. The he Si5380 Reference	e maximum LVDS single-ende ence Manual for recommended	d amplitude c	an be up to 1 ²	10 mV higher	than the TIA/
2. Measured for 153.6 MHz carr	rier frequency. 10	00 mVpp of sinewave noise ad	ded to VDDO	when program	mmed at 3.3 V	Ι.
"AN862: Optimizing Si534x J	es are generated itter Performance	n LVDS mode, with the victim I using non-production engined in Next Generation Internet In terminated when measuring cr	ering modes on frastructure S	only for test. R	efer to applica	ation note,
	Table 5.6	5. LVCMOS Clock Output Sp	ecifications		- C	
Parameter Sv	mbol	Test Condition	Min	Тур	Max	Unit

DC		ion	Min	Тур	Max	Uni	
DC			0.480	\vdash	245.76	MHz	
DC	f _{OUT} < 100 M	lHz	48		52	%	
-	100 MHz < f _{OUT} < 2	45.76 MHz	45	_	55	-	
Т _{SK}	Outputs at 153.6 MHz		0	30	140	ps	
		V	_{DDO} = 3.3 V				
-	OUTx_CMOS_DRV=1	$I_{OH} = -10 \text{ mA}$	V _{DDO} x 0.85	_		V	
-	OUTx_CMOS_DRV=2	I _{OH =} –12 mA		_	_		
-	OUTx_CMOS_DRV=3	I _{OH =} –17 mA		_			
-	.0	V _E	_{DDO} = 2.5 V				
V _{OH}	OUTx_CMOS_DRV=1	I _{OH =} –6 mA	V _{DDO} x 0.85	_	_	V	
	OUTx_CMOS_DRV=2	I _{OH =} –8 mA		_	_		
	OUTx_CMOS_DRV=3	I _{OH =} –11 mA		_	_		
-	V _{DDO} = 1.8 V						
	OUTx_CMOS_DRV=2	I _{OH =} –4 mA	V _{DDO} x 0.85	_		V	
	OUTx_CMOS_DRV=3	I _{OH =} –5 mA					
		V _{OH} OUTx_CMOS_DRV=1 OUTx_CMOS_DRV=2 OUTx_CMOS_DRV=3 OUTx_CMOS_DRV=1 OUTx_CMOS_DRV=2 OUTx_CMOS_DRV=3 OUTx_CMOS_DRV=2 OUTx_CMOS_DRV=3	$V_{OH} = -10 \text{ mA}$ $OUTx_CMOS_DRV=1 I_{OH} = -10 \text{ mA}$ $OUTx_CMOS_DRV=2 I_{OH} = -12 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -17 \text{ mA}$ $V_{OH} = -17 \text{ mA}$ $OUTx_CMOS_DRV=1 I_{OH} = -6 \text{ mA}$ $OUTx_CMOS_DRV=2 I_{OH} = -8 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -11 \text{ mA}$ V_{D} $OUTx_CMOS_DRV=2 I_{OH} = -4 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -4 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -5 \text{ mA}$	$V_{DDO} = 3.3 V$ $OUTx_CMOS_DRV=1 I_{OH} = -10 \text{ mA}$ $OUTx_CMOS_DRV=2 I_{OH} = -12 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -17 \text{ mA}$ $V_{DDO} = 2.5 V$ $V_{OH} OUTx_CMOS_DRV=1 I_{OH} = -6 \text{ mA}$ $OUTx_CMOS_DRV=2 I_{OH} = -8 \text{ mA}$ $OUTx_CMOS_DRV=3 I_{OH} = -11 \text{ mA}$ $V_{DDO} = 1.8 V$ $OUTx_CMOS_DRV=2 I_{OH} = -4 \text{ mA}$ $V_{DDO} \times 0.85$ $OUTx_CMOS_DRV=2 I_{OH} = -4 \text{ mA}$ $V_{DDO} \times 0.85$ $OUTx_CMOS_DRV=2 I_{OH} = -4 \text{ mA}$ $V_{DDO} \times 0.85$ $OUTx_CMOS_DRV=2 I_{OH} = -5 \text{ mA}$	VDDO = 3.3 V OUTx_CMOS_DRV=1 I _{OH} = -10 mA V _{DDO} × 0.85 OUTx_CMOS_DRV=2 I _{OH} = -12 mA OUTx_CMOS_DRV=3 I _{OH} = -17 mA OUTx_CMOS_DRV=3 I _{OH} = -17 mA VOH OUTx_CMOS_DRV=1 I _{OH} = -6 mA V _{DDO} × 0.85 OUTx_CMOS_DRV=2 I _{OH} = -8 mA OUTx_CMOS_DRV=3 I _{OH} = -11 mA OUTx_CMOS_DRV=2 I _{OH} = -4 mA V _{DDO} × 0.85 OUTx_CMOS_DRV=2 I _{OH} = -4 mA V _{DDO} × 0.85 OUTx_CMOS_DRV=3 I _{OH} = -5 mA	VDDO = 3.3 V OUTx_CMOS_DRV=1 I _{OH} = -10 mA VDDO x 0.85 OUTx_CMOS_DRV=2 I _{OH} = -12 mA OUTx_CMOS_DRV=3 I _{OH} = -17 mA OUTx_CMOS_DRV=3 I _{OH} = -17 mA VOH OUTx_CMOS_DRV=1 I _{OH} = -6 mA V _{DDO} x 0.85 OUTx_CMOS_DRV=2 I _{OH} = -8 mA OUTx_CMOS_DRV=3 I _{OH} = -11 mA OUTx_CMOS_DRV=2 I _{OH} = -4 mA V _{DDO} x 0.85 OUTx_CMOS_DRV=2 I _{OH} = -4 mA V _{DDO} x 0.85	

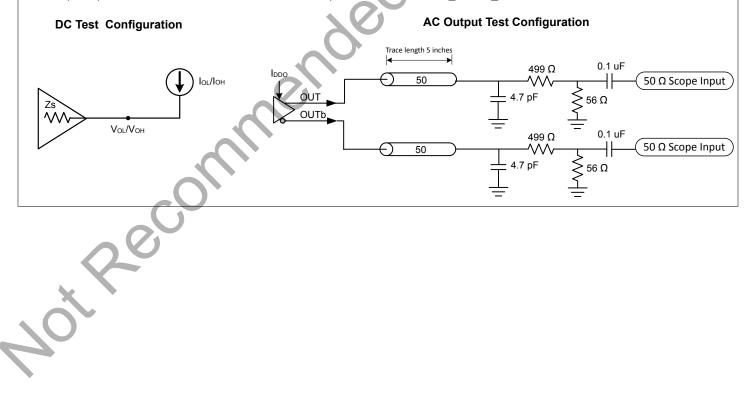
Table 5.6. LVCMOS Clock Output Specifications

Parameter	Symbol	Test Conditi	on	Min	Тур	Max	Unit		
		V _{DDO} = 3.3 V							
		OUTx_CMOS_DRV=1	I _{OL =} 10 mA	_	_	V _{DDO} x 0.15	V		
		OUTx_CMOS_DRV=2	I _{OL =} 12 mA	_	-				
		OUTx_CMOS_DRV=3	I _{OL =} 17 mA	_	_	-	(
			V	_{DDO} = 2.5 V			5		
Output Voltage Low ^{1, 2, 3}	V _{OL}	OUTx_CMOS_DRV=1	I _{OL =} 6 mA	_	_	V _{DDO} x 0.15	V		
		OUTx_CMOS_DRV=2	I _{OL =} 8 mA	_	_		2		
		OUTx_CMOS_DRV=3	I _{OL =} 11 mA	_	_	0.0			
			V	_{DDO} = 1.8 V					
		OUTx_CMOS_DRV=2	I _{OL =} 4 mA	_	_	V _{DDO} x 0.15	V		
		OUTx_CMOS_DRV=3	I _{OL =} 5 mA	-	4	-			
LVCMOS Rise and Fall	tr/tf	V _{DDO} = 3.3	V _{DDO} = 3.3 V		400	600	ps		
Times ³		V _{DDO} = 2.5	V	30	450	600	ps		
(20% to 80%)		V _{DDO} = 1.8	V	-	550	750	ps		

Notes:

1. Driver strength is a register programmable setting and stored in NVM. Options are OUTx_CMOS_DRV = 1, 2, 3. Refer to the Si5380 Reference Manual for recommended output register settings.

- 2. I_{OL}/I_{OH} is measured at V_{OL}/V_{OH} as shown in the DC test configuration
- 3. A 5 pF capacitive load is assumed. The LVCMOS outputs were set to OUTx_CMOS_DRV = 3.



Pins (LOLb, INTF					
	RD, SDA/SDIO ² , A1/SDO)				
V _{OH}	I _{OH} = -2 mA	V _{DDIO} x 0.85	_	_	V
V _{OL}	I _{OL} = 2 mA	—	—	V _{DDIO} x 0.15	V
	V _{OH}	V_{OH} $I_{OH} = -2 \text{ mA}$	V_{OH} $I_{OH} = -2 \text{ mA}$ $V_{DDIO} \times 0.85$	V_{OH} $I_{OH} = -2 \text{ mA}$ $V_{DDIO} \times -$ 0.85	V_{OH} $I_{OH} = -2 \text{ mA}$ $V_{DDIO} x$ V_{OL} $I_{OL} = 2 \text{ mA}$ $V_{DDIO} x$

Table 5.7. Output Serial and Status Pin Specifications

Notes:

1. V_{DDIO} is determined by the IO_VDD_SEL bit. It is selectable as V_{DDA} or V_{DD}. See the Si5380 Reference Manual for more details on the register settings.

2. The V_{OH} specification does not apply to the open-drain SDA/SDIO output when the serial interface is in I2C mode or is unused, with I2C_SEL pulled high internally. V_{OL} remains valid in all cases.

Table 5.8. Performance Characteristics

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
PLL Bandwidth Programming Range ¹	f _{BW}	Bandwidth is register programmable	0.1	_	4000	Hz
Initial Start-Up Time	t _{start}	Time from power-up to when the device gener- ates free-running clocks) -	370	450	ms
PLL Lock Time ²	t _{ACQ}	Fastlock enabled F _{IN} = 19.2 MHz		280	300	ms
POR to Serial Interface Ready ³	t _{RDY}		_	—	15	ms
Output Delay Adjustment	t _{DELAY_int}	f _{VCO} = 14.7456 GHz	_	68	_	ps
	t _{RANGE}	±128 / f _{VCO}	_	8.6	_	ns
Jitter Peaking	Јрк	Measured with a frequen- cy plan running a 24.576 MHz input, 24.576 MHz output, and a Loop Band- width of 4 Hz	_	_	0.1	dB
Jitter Tolerance	J _{TOL}	Compliant with G.8262 Options 1 and 2 Carrier Frequency = 2.103125 GHz; Jitter Modulation Frequency = 10 Hz	_	3180	_	UI pk-pk
Maximum Phase Transient Dur- ing a Hitless Switch	tswiтсн	Only valid for a single au- tomatic switch between two input clocks at same frequency		_	2.0	ns
		Only valid for a single manual switch between two input clocks at same frequency		_	1.3	ns
Pull-in Range	ω _P		-20		20	ppm

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Input-to-Output Delay Variation	t _{IODELAY}	Note 5			1.8	ns
-	t _{ZDELAY}	Note 6	—	110	—	ps
RMS Phase Jitter ⁴	J_{GEN}	12 kHz to 20 MHz	_	65	80	fs rms
		(measured @ 983.04 MHz)				C
Phase Noise Performance ⁴	PN	10Hz	_	-72	_	dBc/Hz
(122.88 MHz Carrier		100 Hz	_	-98	_ •	dBc/Hz
Frequency)		1 kHz	—	-126	- C	dBc/Hz
		10 kHz	_	-140	- Ar	dBc/Hz
		100 kHz	_	-148		dBc/Hz
		1 MHz	_	-154	V -	dBc/Hz
		10 MHz	_	-165	_	dBc/Hz
Spur Performance ⁴ (122.88	SPUR	Up to 1 MHz offset	_	-103	—	dBc
MHz Carrier Frequency)		From 1 MHz to 30 MHz offset	-	-95	_	dBc

Notes:

1. Actual loop bandwidth might be lower; refer to ClockBuilder Pro for actual value on your frequency plan.

2. Lock Time can vary significantly depending on several parameters, such as bandwidths, LOL thresholds, etc. For this case, lock time was measured with nominal and fastlock bandwidths both set to 100 Hz, LOL set/clear thresholds of 3/0.3 ppm respectively, using IN0 as clock reference by removing the reference and enabling it again, then measuring the delta time between the first rising edge of the clock reference and the LOL indicator de-assertion.

3. Measured as time from valid V_{DD}/V_{DDA} rails (both >90% of settled voltage) to when the serial interface is ready to respond to commands.

4. Jitter generation test conditions: f_{IN} = 30.72 MHz, 3.3V LVPECL, DSPLL LBW = 100 Hz. Jitter integrated from 12 kHz to 20 MHz offset. Does not include jitter from PLL input reference.

5. Measured between a common 2 MHz input and 2 MHz output with different N-dividers on the same unit and a loop bandwidth of 4 kHz. These output frequencies are generated using non-production engineering modes only for test.

6. Delay between reference and feedback input both clocks at 10 MHz and same slew rate. Ref clock rise time must be <200 ps. These output frequencies are generated using non-production engineering modes only for test.

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Parameter	Symbol	Test Condition		rd Mode		Mode	Uni
			100	kbps	400	kbps	-
			Min	Мах	Min	Max	
SCL Clock Frequency	f _{SCL}		_	100	—	400	kHz
SMBus Timeout	_	When Timeout is Ena- bled	25	35	25	35	ms
Hold Time (Repeated) START Condition	t _{HD:STA}		4.0	_	0.6	S	μs
Low Period of the SCL Clock	t _{LOW}		4.7		1.3	C	μs
HIGH Period of the SCL Clock	t _{HIGH}		4.0	_	0.6	2 -	μs
Set-up Time for a Repeated START Condition	t _{SU:STA}		4.7		0.6		μs
Data Hold Time	t _{HD:DAT}		100	X	100	_	ns
Data Set-up Time	t _{SU:DAT}		250	-	100	_	ns
Rise Time of Both SDA and SCL Signals	tr		5	1000	20	300	ns
Fall Time of Both SDA and SCL Signals	t _f	2	X	300	_	300	ns
Set-up Time for STOP Con- dition	t _{SU:STO}		4.0	_	0.6		μs
Bus Free Time between a STOP and START Condition	t _{BUF}		4.7	_	1.3	_	μs
Data Valid Time	t _{VD:DAT}			3.45		0.9	μs
Data Valid Acknowledge Time	t _{VD:ACK}	V		3.45	_	0.9	μs
Data Valid Acknowledge Time	SU						

Table 5.9. I²C Timing Specifications (SCL, SDA)

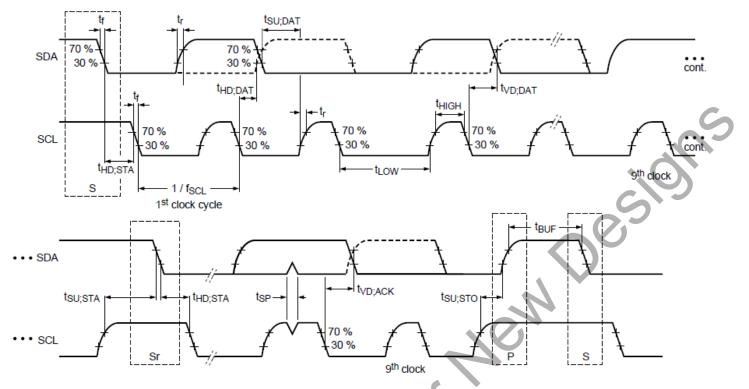


Figure 5.1. I²C Serial Prot Timing Standard and Fast Modes

Parameter	Symbol	Min	Тур	Max	Unit
SCLK Frequency	f _{SPI}	—	_	20	MHz
SCLK Duty Cycle	T _{DC}	40	_	60	%
SCLK Period	Τ _C	50	_	_	ns
Delay Time, SCLK Fall to SDO Active	T _{D1}	_	_	18	ns
Delay Time, SCLK Fall to SDO	T _{D2}	_	_	15	ns
Delay Time, CSb Rise to SDO Tri-State	T _{D3}	_	_	15	ns
Setup Time, CSb to SCLK	T _{SU1}	5			ns
Hold Time, SCLK Fall to CSb	T _{H1}	5	_	_	ns
Setup Time, SDI to SCLK Rise	T _{SU2}	5	_	_	ns
Hold Time, SDI to SCLK Rise	T _{H2}	5	_	_	ns
Delay Time Between Chip Selects (CSb)	T _{CS}	2	—		T _c

Table 5.10. SPI Timing Specifications (4-Wire)

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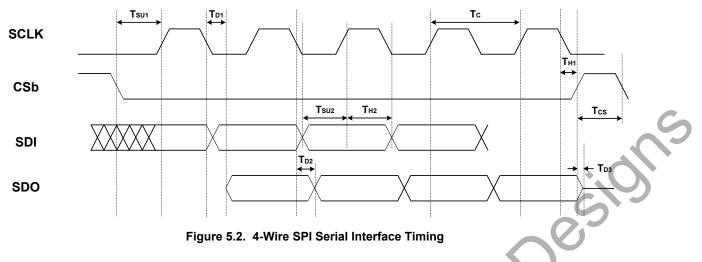


Figure 5.2. 4-Wire SPI Serial Interface Timing

Table 5.11.	SPI Timing	Specifications ((3-Wire)
-------------	------------	------------------	----------

Parameter	Symbol	Min	Тур	Мах	Unit
SCLK Frequency	f _{SPI}			20	MHz
SCLK Duty Cycle	T _{DC}	40	-	60	%
SCLK Period	T _C	50	_	_	ns
Delay Time, SCLK Fall to SDIO Turn-on	T _{D1}	X	_	20	ns
Delay Time, SCLK Fall to SDIO Next-bit	T _{D2}	-	_	15	ns
Delay Time, CSb Rise to SDIO Tri-State	Т _{D3}	_	_	15	ns
Setup Time, CSb to SCLK	Tsu1	5	_	_	ns
Hold Time, SCLK Fall to CSb	T _{H1}	5	_	_	ns
Setup Time, SDI to SCLK Rise	T _{SU2}	5	_	_	ns
Hold Time, SDI to SCLK Rise	T _{H2}	5	_	_	ns
Delay Time Between Chip Selects (CSb)	T _{CS}	2	_	_	T _c

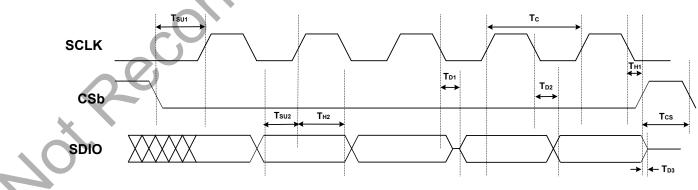


Figure 5.3. 3-Wire SPI Serial Interface Timing

Table 5.12. Crystal Specifications

Parameter	Symbol	Test Condition	Min	Тур	Мах	Unit
Crystal Frequency ¹	f _{XTAL}		—	54	_	MHz
Total Frequency Tolerance ²	f _{RANGE}		-100	_	+100	ppm
Load Capacitance	CL		_	8	_	pF
Equivalent Series Resistance	r _{ESR}	Refer to the Family Referen	nce Manual to	determine ES	SR and shunt of	capacitance.
Shunt Capacitance	Co				Ċ	\mathbf{S}
Crystal Drive Level	dL	The crystal resonator must be able to tolerate 350 µW of drive level	_	-	350	μW

Notes:

1. See the Si5380 Reference Manual for a list of qualified 54 MHz crystals. The Si5380 is designed to work with crystals that meet these specifications.

2. Includes initial tolerance, drift after reflow, change over temperature (-40 °C to +85 °C), V_{DD} variation, load pulling, and aging.

Parameter	Symbol	Test Condition	Value	Unit
Si5380–64QFN		\sim		
Thermal Resistance	θ _{JA}	Still Air	22	°C/W
Junction to Ambient		Air Flow 1 m/s	19.4	
		Air Flow 2 m/s	18.3	
Thermal Resistance	θJC		9.5	
Junction to Case				
Thermal Resistance	θ _{JB}		9.4	
Junction to Board				
Thermal Resistance	Ψ _{JB}		9.3	
Junction to Board				
Thermal Resistance	Ψ _{JT}		0.2	
Junction to Top Center				
Note:				1
1. Based on PCB Dimension: 3x4.5", PC	B Thickness: 1.6 mm, PCB La	nd/Via: 36, Number of Cu La	yers: 4.	

Table 5.13. Thermal Characteristics

Parameter	Symbol	Test Condition	Value	Unit
DC Supply Voltage	V _{DD}		-0.5 to 3.8	V
	V _{DDA}		-0.5 to 3.8	V
	V _{DDO}		-0.5 to 3.8	V
Input Voltage Range	V _{I15}	IN0-IN3/FB_IN	-0.85 to 3.8	V
	V _{I2}	IN_SEL[1:0],	-0.5 to 3.8	NO
		RSTb, PDNb,OEb, SYNCb,	0	2
		I2C_SEL, SCLK,	0	
		A0/CSb, A1/SDO,	\mathbf{N}	
		SDA/SDIO		
	V _{I3}	XA/XB	-0.5 to 2.7	V
Latch-up Tolerance	LU		JESD78 Compliant	
ESD Tolerance	НВМ	100 pF, 1.5 kΩ	2.0	kV
Storage Temperature Range	T _{STG}		-55 to 150	°C
Max Junction Temperature in Operation	T _{JCT}	<u> </u>	125	°C
Soldering Temperature (Pb-free profile) ⁴	Т _{РЕАК}		260	°C
Soldering Temperature Time at T_{PEAK} (Pb-free profile) ⁴	TP		20 to 40	sec
Notos:		1		1

Table 5.14. Absolute Maximum Ratings 1, 2, 3, 4

Notes:

1. Permanent device damage may occur if the absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as specified in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

2.64-QFN is RoHS-6 compliant.

OtRei

3. For MSL rating and additional packaging information, go to http://www.silabs.com/support/quality/pages/RoHSInformation.aspx.

4. The device is compliant with JEDEC J-STD-020.

5. The minimum voltage at these pins can be as low as -1.0 V when an AC input signal is applied. See Table 5.3 Input Clock Specifications on page 24 spec for Single-ended AC-coupled f_{IN} < 245.76 MHz.

6. Typical Application Diagrams

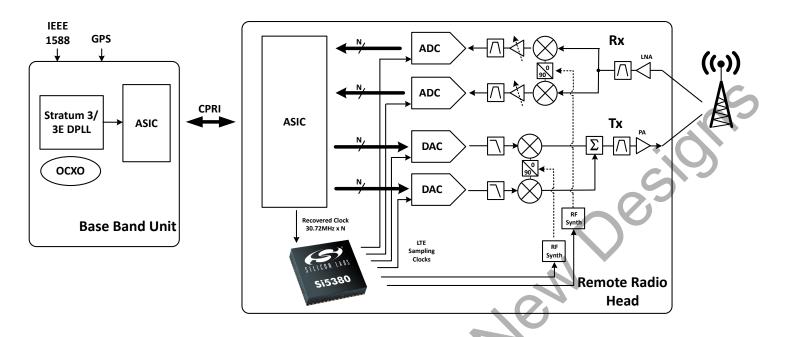
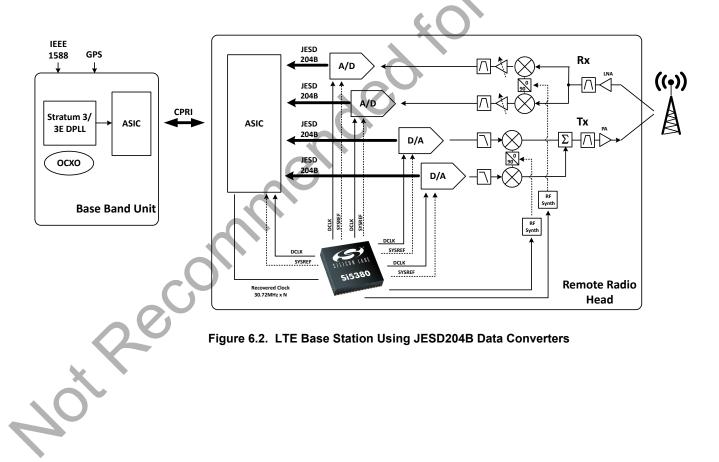
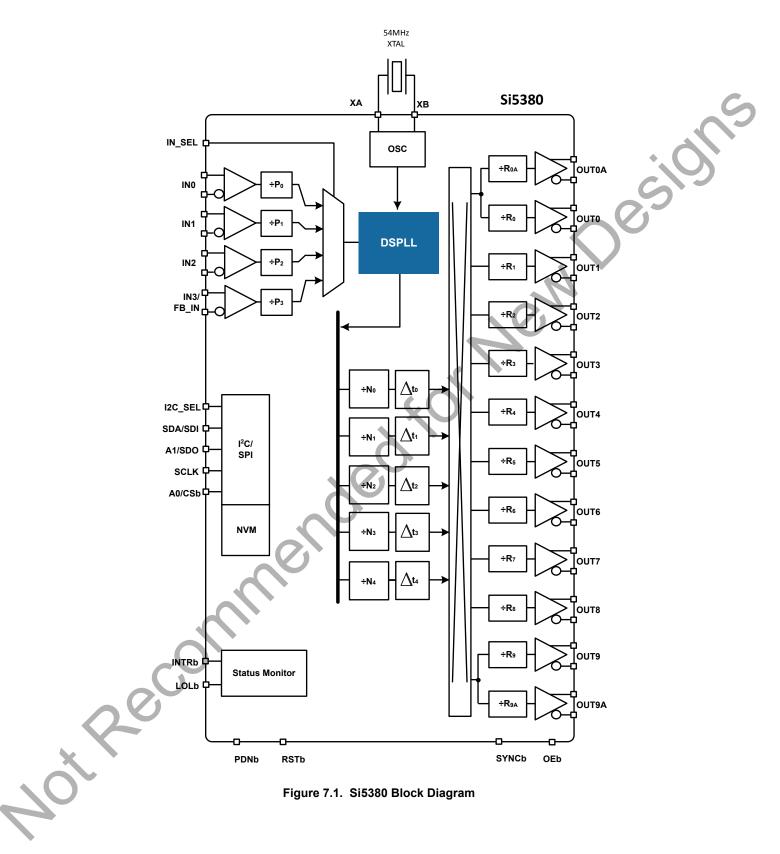


Figure 6.1. LTE Base Station Remote Radio Head



7. Detailed Block Diagram





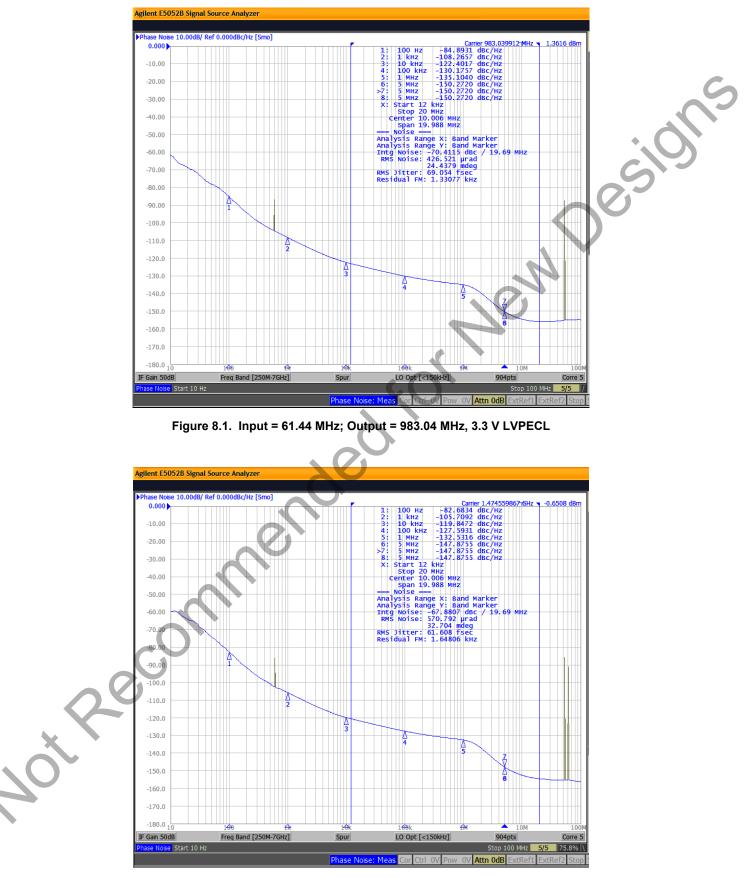


Figure 8.2. Input = 61.44 MHz; Output = 1,474.56 MHz, 3.3 V LVPECL

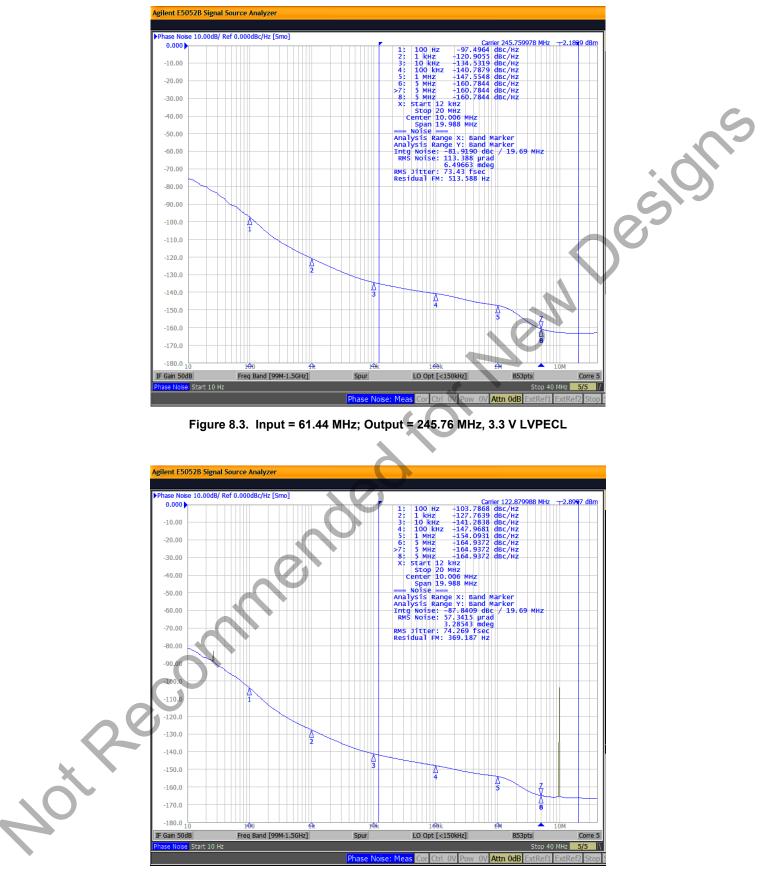


Figure 8.4. Input = 61.44 MHz; Output = 122.88 MHz, 3.3 V LVPECL

9. Pin Description

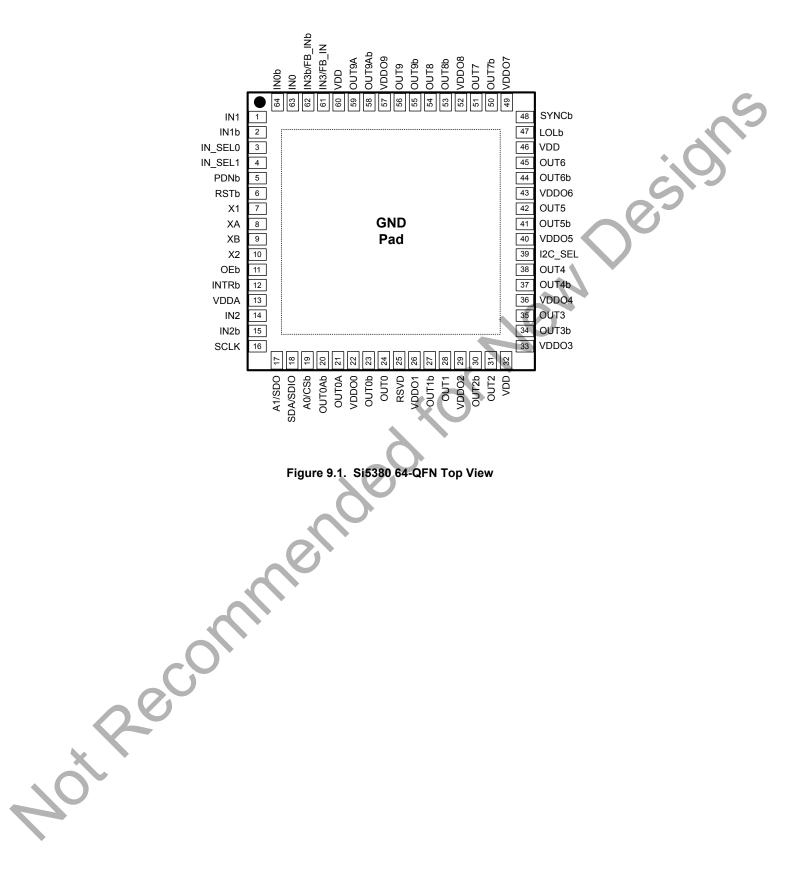


Table 9.1. Pin Descriptions

	Pin Number	Pin Type ¹	Function
XA	8	I	Crystal Input. Input pin for external crystal (XTAL). Alterna-
ХВ	9	I	 tively these pins can be driven with an external reference clock (REFCLK). An internal register bit selects XTAL or REFCLK mode. Default is XTAL mode. Single-ended inputs must be connected to the XA pin, with the XB pin appropri- ately terminated.
X1	7	I	XTAL Shield. Connect these pins directly to the crystal
X2	10	I	ground pins. Both the X1/X2 pins and Crystal ground pins should be separated from the PCB ground plane. Refer to the Reference Manual for layout guidelines.
INO	63	I	Clock Inputs. These pins accept an input clock for syn-
IN0b	64	I	 chronizing the device. They support both differential and single-ended clock signals. Refer to 3.3.1 Input Configura-
IN1	1	I	tion and Terminations for input termination options. These pins are high-impedance and must be terminated externally
IN1b	2	I	when being used. The negative side of the differential input must be ac-grounded when accepting a single-ended clock
IN2	14	I	Unused inputs may be left unconnected.
IN2b	15	I	
IN3/FB_IN	61	I	Clock Input 3/External Feedback Input.
IN3b/FB_INb	62	5	By default, these pins are used as the 4 th clock input (IN3/ IN3b). They can also be used as the external feedback in- put (FB_IN/FB_INb) for the optional zero delay mode. See section 5.3.6 for details on the optional zero delay mode.
		enor	
	sonn		

Pin Name	Pin Number	Pin Type ¹	Function
OUT0A	21	0	Output Clocks. These output clocks support programma-
OUT0Ab	20	0	ble signal amplitude and common mode voltage. Desired output signal format is configurable using register control.
OUT0	24	0	Termination recommendations are provided in 3.5.5 LVCMOS Output Terminations. Unused outputs
OUT0b	23	0	should be left unconnected.
OUT1	28	0	
OUT1b	27	0	
OUT2	31	0	
OUT2b	30	0	Sis
OUT3	35	0	
OUT3b	34	0	
OUT4	38	0	
OUT4b	37	0	4
OUT5	42	0	
OUT5b	41	0	
OUT6	45	0	
OUT6b	44	0	
OUT7	51	0	
OUT7b	50	0	
OUT8	54	0	
OUT8b	53	0	
OUT9	56	0	
OUT9b	55	0	
OUT9A	59	0 0	
OUT9Ab	58	0	
Serial Interface			
I2C_SEL	39	I	I2C Select. This pin selects the serial interface mode as I^2C (I2C_SEL = 1) or SPI (I2C_SEL = 0). This pin is internally pulled high.
SDA/SDIO	18	I/O	Serial Data Interface. This is the bidirectional data pin (SDA) for the I ² C mode, the bidirectional data pin (SDIO) in the 3-wire SPI mode, or the input data pin (SDI) in 4-wire SPI mode. When in I ² C mode or unused, this pin must be pulled-up using an external resistor of >= 1 k Ω . No pull-up resistor is needed when in SPI mode.
A1/SDO	17	I/O	Address Select 1/Serial Data Output. In I ² C mode this pin functions as the A1 address input pin. In 4-wire SPI mode, this is the serial data output (SDO) pin. This pin should be externally pulled up or down when unused.
SCLK	16	I	Serial Clock Input. This pin functions as the serial clock input for both I ² C and SPI modes. When in I ² C mode or unused, this pin must be pulled-up using an external resistor of >= 1 k Ω . No pull-up resistor is needed when in SPI mode.

•

	Pin Number	Pin Type ¹	Function
A0/CSb	19	I	Address Select 0/Chip Select. This pin functions as the hardware controlled address A0 in I^2C mode. In SPI mode, this pin functions as the chip select input (active low). This pin is internally pulled-up.
Control/Status			
INTRb	12	0	Interrupt. ² This pin is asserted low when a change in device status has occurred. This pin must be pulled-up externally using a resistor of >= 1 k Ω . It should be left unconnected when not in use.
PDNb	5	I	Power Down. ² The device enters into a low power mode when this pin is pulled low. This pin is internally pulled-up. It can be left unconnected when not in use.
RSTb	6	I	Device Reset. ² Active low input that performs power-on reset (POR) of the device. Resets all internal logic to a known state and forces the device registers to their default values. Clock outputs are disabled during reset. This pin is internally pulled-up.
OEb	11	I	Output Enable. ² This pin disables all outputs when held high. This pin is internally pulled low and can be left unconnected when not in use.
LOLb	47	0	Loss Of Lock. ² This output pin indicates when the DSPLL is locked (high) or out-of-lock (low). When in use, this pin must be pulled-up using an external resistor of >= 1 k Ω . It can be left unconnected when not in use.
SYNCb	48	20C	Output Clock Synchronization. ² An active low signal on this pin resets the output dividers for the purpose of realigning the output clocks. This pin is internally pulled-up and can be left unconnected when not in use.
IN_SEL0	3		Input Reference Select. ² The IN_SEL[1:0] pins are used
IN_SEL1	4	C I	in manual pin controlled mode to select the active clock in- put as shown in Table 3.2 Table 6.2 on page 10. These pins are internally pulled-down and may be left unconnected when unused.
RSVD	25		Reserved. Leave disconnected.
ower			
VDD	32	Р	Core Supply Voltage. The device operates from a 1.8 V
VDD	46	Р	supply. A 1 µF bypass capacitor should be placed very close to each pin.
VDD	60	Р	
VDDA	13	Р	Core Supply Voltage 3.3 V . This core supply pin requires a 3.3 V power source. A 1 µF bypass capacitor should be placed very close to this pin.

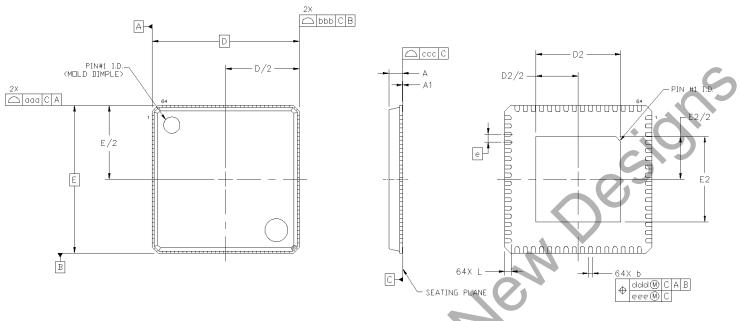
Pin Name	Pin Number	Pin Type ¹	Function
VDD00	22	Р	Output Clock Supply Voltage. Supply voltage (3.3 V, 2.5
VDDO1	26	Р	V, 1.8 V) for OUTx, OUTxb Outputs. Note that VDDO0 supplies power to OUT0 and OUT0A; VDDO9 supplies
VDDO2	29	Р	power to OUT9 and OUT9A. Leave VDDO pins of unused output drivers unconnected. An alternative option is to con-
VDDO3	33	Р	nect the VDDO pin to a power supply and disable the output
VDDO4	36	Р	 driver to minimize current consumption. A 1 µF bypass capacitor should be placed very close to each connected
VDDO5	40	Р	VDDO pin.
VDDO6	43	Р	
VDDO7	49	Р	
VDDO8	52	Р	
VDDO9	57	Р	
GND PAD		Р	Ground Pad . This pad provides connection to ground and must be connected for proper operation.

Note:

1. I = Input, O = Output, P = Power

.tre 2. The IO_VDD_SEL control bit (0x0943 bit 0) selects 3.3 V or 1.8 V operation.

10. Package Outline





Dimension	MIN	NOM	MAX
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D	0	9.00 BSC	
D2	5.10	5.20	5.30
e		0.50 BSC	
E ,	~	9.00 BSC	
E2	5.10	5.20	5.30
L	0.30	0.40	0.50
aaa	_		0.15
bbb	—	_	0.10
CCC	_	_	0.08
ddd	_	_	0.10

Table 10.1. Package Diagram Dimensions

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

3. This drawing conforms to the JEDEC Solid State Outline MO-220.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. PCB Land Pattern

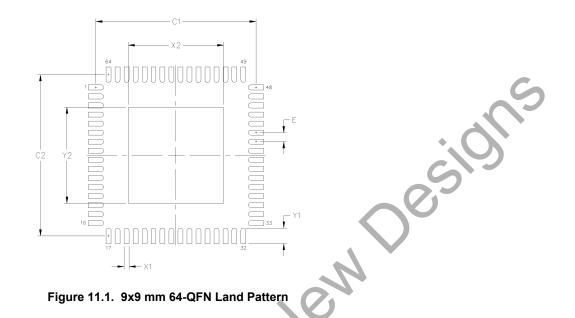


Table 11.1. PCB Land Pattern Dimensions

Dimension	Max
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	5.30
Y2	5.30
Notes:	

General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- 3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition is calculated based on a fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

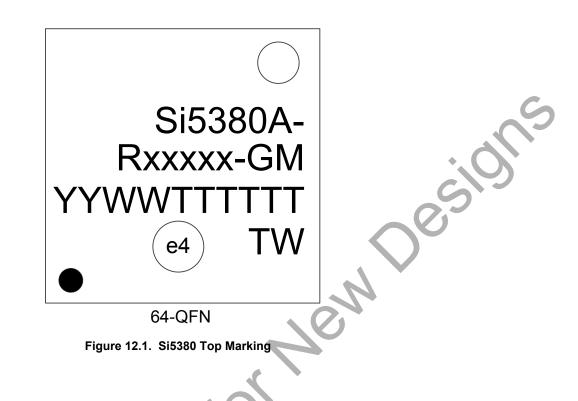
Stencil Design

- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
- 4. A 3x3 array of 1.25 mm square openings on 1.80 mm pitch should be used for the center ground pad.

Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

12. Top Marking





Line	Characters	Description
1	Si5380A-	Base part number for Ultra Low Phase Noise, 12-output JESD204B Clock Generator:
		Si5380A: 12-output clock generator; 64-QFN
		– = Dash character.
2	Rxxxx-GM	R = Product revision. (See Ordering Guide for current ordering revision).
	2	xxxxx = Customer specific NVM sequence number. Optional NVM code assigned for custom, factory pre-programmed devices.
		Characters are not included for standard, factory default configured devices. See Or- dering Guide for more information.
		-GM = Package (QFN) type and temperature range (–40 to +85 °C).
3	YYWWITITTT	YYWW = Characters correspond to the year (YY) and work week (WW) of package assembly.
	20	TTTTTT = Manufacturing trace code.
4	Circle w/ 1.6 mm diameter	Pin 1 indicator; left-justified
X	e4	Pb-free symbol; Center-Justified
$\langle O \rangle$	ТW	TW = Taiwan; Country of Origin (ISO Abbreviation)
	1	1

13. Device Errata

Log in or register at www.silabs.com to access the device errata document.

Recommended to Membershy

14. Document Change List

Recommended for New Deside 14.1 Revision 1.0

July 19, 2016

· Initial release.

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